STF3LN80K5



N-channel 800 V, 2.75 Ω typ., 2 A MDmesh™ K5 Power MOSFET in a TO-220FP package

Datasheet - production data

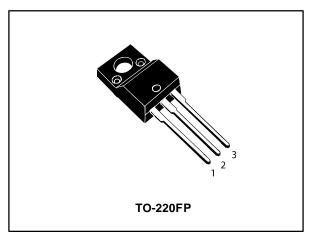
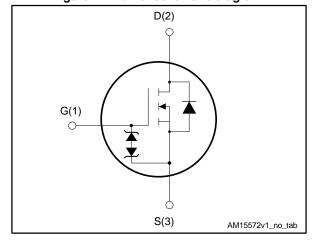


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max	ΙD
STF3LN80K5	800 V	3.25 Ω	2 A

- Industry's lowest R_{DS(on)} x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

Applications

• Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Table 1: Device summary

Order code	Marking	Package	Packing
STF3LN80K5	3LN80K5	TO-220FP	Tube

Contents STF3LN80K5

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STF3LN80K5 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vgs	Gate-source voltage	± 30	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	2	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	1.25	Α
I _D ⁽²⁾	Drain current (pulsed)	8	Α
P _{TOT}	Total dissipation at $T_C = 25$ °C	20	W
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T_C = 25 °C)	nal 2500	
dv/dt (3)	Peak diode recovery voltage slope	4.5	V/ns
dv/dt (4)	MOSFET dv/dt ruggedness	50 V	
T _{stg}	Storage temperature range	55 to 150	°C
Tj	Operating junction temperature range	- 55 to 150	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	6.25	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T _{jmax})	0.7	Α
Eas	Single pulse avalanche energy (starting $T_j = 25^{\circ}C$, $I_D = I_{AR}$; $V_{DD} = 50 \text{ V}$)	155	mJ

⁽¹⁾Limited by maximum junction temperature.

⁽²⁾Pulse width limited by safe operating area.

 $^{^{(3)}}I_{SD} \leq 2$ A, di/dt \leq 100 A/ μ s; VDSpeak < V(BR)DSS, VDD = 640 V

 $^{^{(4)}}V_{DS} \le 640 \text{ V}.$

Electrical characteristics STF3LN80K5

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5: On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	800			V
Zero gate voltage drain current		$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
		$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V},$ $T_{C} = 125 \text{ °C}^{(1)}$			50	μΑ
Igss	Gate body leakage current	V _{GS} = ± 20 V, V _{GS} = 0 V			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 1 A		2.75	3.25	Ω

Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	102	ı	pF
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$	-	11	ı	pF
Crss	Reverse transfer capacitance	Ves = 0 V	-	0.1	ı	pF
Cotr ⁽¹⁾	Equivalent capacitance time related	V 0 to 640 V V 0 V	-	20	-	pF
C _{oer} (2)	Equivalent capacitance energy related	$V_{DS} = 0$ to 640 V, $V_{GS} = 0$ V	-	7	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	12	-	Ω
Qg	Total gate charge	$V_{DD} = 640 \text{ V}, I_D = 2 \text{ A},$	-	2.63	•	nC
Qgs	Gate-source charge	V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge	-	0.91	-	nC
Q _{gd}	Gate-drain charge	behavior")	-	1.53	-	nC

Notes:

 $^{^{(1)}}$ Defined by design, not subject to production test.

 $^{^{(1)}}$ Time related is defined as a constant equivalent capacitance giving the same charging time as C_{OSS} when V_{DS} increases from 0 to 80% V_{DSS}

 $^{^{(2)}}$ Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 400 \text{ V}, I_D = 1 \text{ A}, R_G = 4.7 \Omega,$	-	6.2	-	ns
tr	Rise time	V _{GS} = 10 V (see Figure 14: "Test	-	7	-	ns
t _{d(off)}	Turn-off delay time	circuit for resistive load switching times" and Figure 19: "Switching	-	30	-	ns
tf	Fall time	time waveform")	-	26	-	ns

Table 8: Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		2	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		8	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 2 A, V _{GS} = 0 V	-		1.5	V
trr	Reverse recovery time		-	210		ns
Qrr	Reverse recovery charge	I _{SD} = 2 A, di/dt = 100 A/μs, V _{DD} = 60 V (see <i>Figure 16: "Test</i> circuit for inductive load switching	-	0.8		μC
I _{RRM}	Reverse recovery current	and diode recovery times")	-	7.6		Α
t _{rr}	Reverse recovery time	I _{SD} = 2 A, di/dt = 100 A/µs,	-	345		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V, T _i = 150 °C, (see <i>Figure 16: "Test circuit for</i>	-	1.2		μC
I _{RRM}	Reverse recovery current	inductive load switching and diode recovery times")	-	7.2		Α

Notes:

Table 9: Gate-source Zener diode

Symb	l Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)G}	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}, I_{D} = 0 \text{ A}$	30	-	-	V

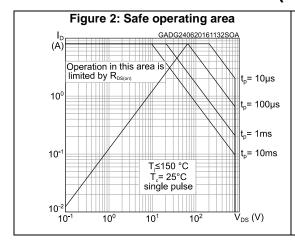
The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

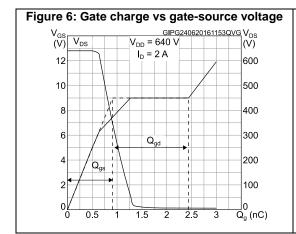


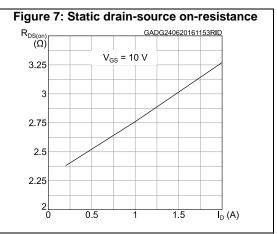
⁽¹⁾Pulse width limited by safe operating area.

 $^{^{(2)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%.

2.1 Electrical characteristics (curves)







STF3LN80K5 Electrical characteristics

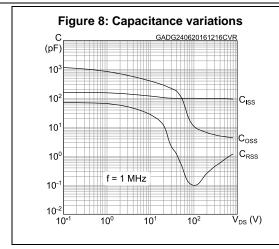


Figure 9: Source-drain diode forward characteristics V_{SD} GADG240620161227SDF (V)1 $T_{j} = -50 \, ^{\circ}C$ 0.8 $T_{j} = 25 \, ^{\circ}C$ 0.6

0.5

0.5

0.5

1.5 I_{SD} I_{SD} I_{SD} I_{SD}

Figure 10: Normalized gate threshold voltage vs temperature

V_{GS(th)}
(norm.)

1.2

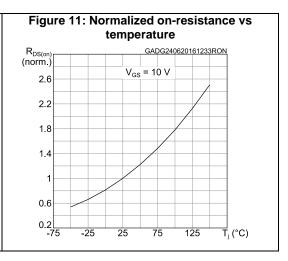
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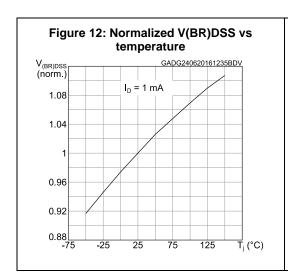
0.8

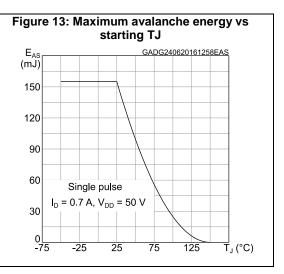
0.6

0.4

-75
-25
25
75
125
T_j (°C)







Test circuits STF3LN80K5

3 Test circuits

lest circuits

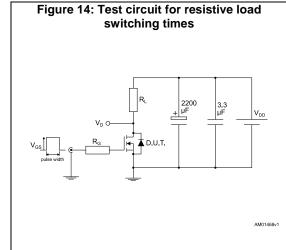


Figure 15: Test circuit for gate charge behavior

VGS RL

VGS PUBLIC PRINCIPLE OF THE PRINC

Figure 16: Test circuit for inductive load switching and diode recovery times

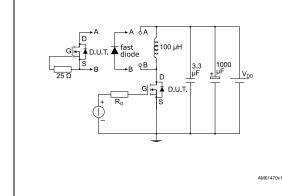


Figure 17: Unclamped inductive load test circuit

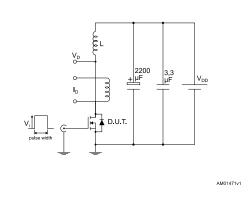


Figure 18: Unclamped inductive waveform

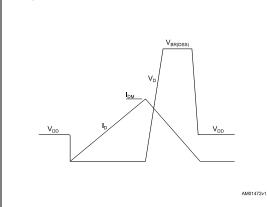
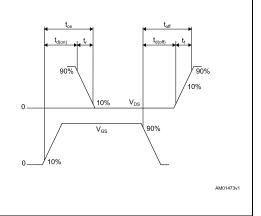


Figure 19: Switching time waveform



STF3LN80K5 Package information

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



4.1 TO-220FP package information

Figure 20: TO-220FP package outline

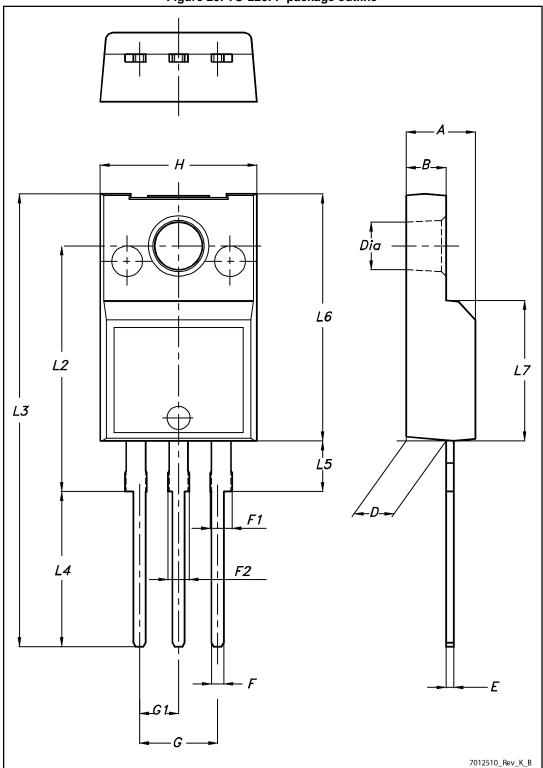


Table 10: TO-220FP package mechanical data

Di	Dim.			
Dim.	Min.	Тур.	Max.	
А	4.4		4.6	
В	2.5		2.7	
D	2.5		2.75	
Е	0.45		0.7	
F	0.75		1	
F1	1.15		1.70	
F2	1.15		1.70	
G	4.95		5.2	
G1	2.4		2.7	
Н	10		10.4	
L2		16		
L3	28.6		30.6	
L4	9.8		10.6	
L5	2.9		3.6	
L6	15.9		16.4	
L7	9		9.3	
Dia	3		3.2	

Revision history STF3LN80K5

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
13-May-2015	1	Initial release
01-Jul-2016	2	Updated title and features in cover page. Updated Table 2: "Absolute maximum ratings" and Section 2: "Electrical characteristics". Added Section 2.1: "2.1 Electrical characteristics (curves)". Minor text changes.

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